

## G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems



Contribution ID: 15

Type: not specified

### **Radiation concerns in the automotive industry mechanisms, standards, typical measurements**

*Wednesday, December 9, 2020 2:30 PM (25 minutes)*

Current and future automotive and autonomous applications are complex, forward-looking systems, involving large quantities of silicon, machine computing power and human brains and tears.

Their quality is prescribed, described and expected by demanding standards. These benevolent dictators set requirements for functional safety and reliability targets and development and manufacturing processes.

Transient faults, including Single Events are one of the key concerns and the system's FIT rate and ability to manage faults are the principal metrics to demonstrate.

This presentation will highlight current and future topics dealing with the evaluation, certification and testing of automotive circuits and systems and will show how testing is the decisive, ultimate proof of design's worthiness.

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**Session Classification:** Session 2 - Atmospheric and terrestrial applications